

**BUL118**

## HIGH VOLTAGE FAST-SWITCHING NPN POWER TRANSISTOR

- NPN TRANSISTOR
- HIGH VOLTAGE CAPABILITY
- LOW SPREAD OF DYNAMIC PARAMETERS
- MINIMUM LOT-TO-LOT SPREAD FOR RELIABLE OPERATION
- VERY HIGH SWITCHING SPEED

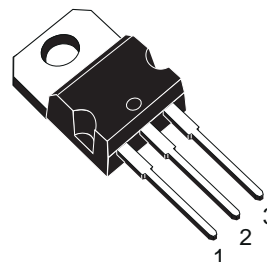
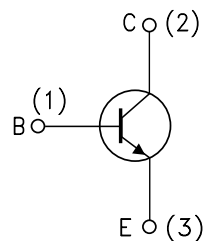
**APPLICATIONS:**

- ELECTRONIC BALLASTS FOR FLUORESCENT LIGHTING

**DESCRIPTION**

The device is manufactured using high voltage Multi Epitaxial Planar technology for high switching speeds and medium voltage capability. It uses a Cellular Emitter structure with planar edge termination to enhance switching speeds while maintaining the wide RBSOA.

The device is designed for use in lighting applications and low cost switch-mode power supplies.

**TO-220****INTERNAL SCHEMATIC DIAGRAM**

SC06960

**ABSOLUTE MAXIMUM RATINGS**

Symbol	Parameter	Value	Unit
$V_{CES}$	Collector-Emitter Voltage ( $V_{BE} = 0$ )	700	V
$V_{CEO}$	Collector-Emitter Voltage ( $I_B = 0$ )	400	V
$V_{EBO}$	Emitter-Base Voltage ( $I_C = 0$ , $I_B < 1.5A$ , $t_p < 10\mu s$ , $T_j < 150^\circ C$ )	$BV_{EBO}$	V
$I_C$	Collector Current	3	A
$I_{CM}$	Collector Peak Current ( $t_p < 5$ ms)	6	A
$I_B$	Base Current	1.5	A
$I_{BM}$	Base Peak Current ( $t_p < 5$ ms)	3	A
$P_{tot}$	Total Dissipation at $T_c = 25^\circ C$	60	W
$T_{stg}$	Storage Temperature	-65 to 150	$^\circ C$

## THERMAL DATA

R <sub>thj-case</sub>	Thermal Resistance Junction-Case	Max	2.08	°C/W
R <sub>thj-amb</sub>	Thermal Resistance Junction-Ambient	Max	62.5	°C/W

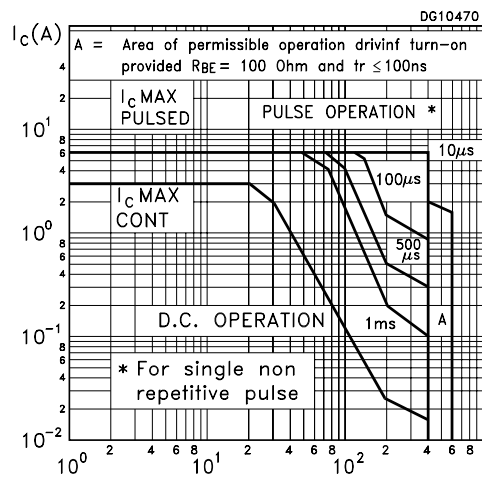
ELECTRICAL CHARACTERISTICS (T<sub>case</sub> = 25 °C unless otherwise specified)

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
I <sub>CES</sub>	Collector Cut-off Current (V <sub>BE</sub> = -1.5 V)	V <sub>CE</sub> = 700 V V <sub>CE</sub> = 700 V      T <sub>J</sub> = 125 °C			100 500	μA μA
BV <sub>EBO</sub>	Emitter-Base Breakdown Voltage (I <sub>C</sub> =0)	I <sub>E</sub> = 10 mA	9		18	V
V <sub>CEO(sus)</sub>	Collector-Emitter Sustaining Voltage	I <sub>C</sub> = 100 mA      L = 25 mH	400			V
I <sub>CEO</sub>	Collector Cut-Off Current (I <sub>B</sub> = 0)	V <sub>CE</sub> = 400 V			250	μA
V <sub>CE(sat)*</sub>	Collector-Emitter Saturation Voltage	I <sub>C</sub> = 0.5 A      I <sub>B</sub> = 0.1 A I <sub>C</sub> = 1 A      I <sub>B</sub> = 0.2 A I <sub>C</sub> = 2 A      I <sub>B</sub> = 0.4 A			0.5 1 1.3	V V V
V <sub>BE(sat)*</sub>	Base-Emitter Saturation Voltage	I <sub>C</sub> = 0.5 A      I <sub>B</sub> = 0.1 A I <sub>C</sub> = 1 A      I <sub>B</sub> = 0.2 A I <sub>C</sub> = 2 A      I <sub>B</sub> = 0.4 A			1.0 1.2 1.3	V V V
h <sub>FE</sub> *	DC Current Gain	I <sub>C</sub> = 10 mA      V <sub>CE</sub> = 5 V I <sub>C</sub> = 0.5 A      V <sub>CE</sub> = 5 V Group A Group B I <sub>C</sub> = 2 A      V <sub>CE</sub> = 5 V	10  10 18 8		22 40	
t <sub>r</sub> t <sub>s</sub> t <sub>f</sub>	RESISTIVE LOAD Resistive Time Storage Time Fall Time	V <sub>CC</sub> = 125 V      I <sub>C</sub> = 1 A I <sub>B1</sub> = 0.2 A      I <sub>B2</sub> = -0.2 A T <sub>p</sub> = 30 μs      (see fig.2)		0.4 3.2 0.25	0.7 4.5 0.4	μs μs μs
t <sub>s</sub> t <sub>f</sub>	INDUCTIVE LOAD Storage Time Fall Time	I <sub>C</sub> = 1 A      I <sub>B1</sub> = 0.2 A V <sub>BEoff</sub> = -5 V      R <sub>BB</sub> = 0 Ω V <sub>clamp</sub> = 200 V      L = 50mH (see fig.1)		0.8 0.16		μs μs

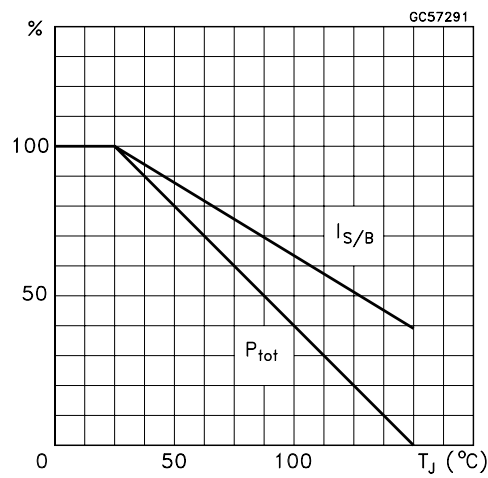
\* Pulsed: Pulse duration = 300 μs, duty cycle 1.5 %

Note : Product is pre-selected in DC current gain (GROUP A and GROUP B). STMicroelectronics reserves the right to ship either groups according to production availability. Please contact your nearest STMicroelectronics sales office for delivery details.

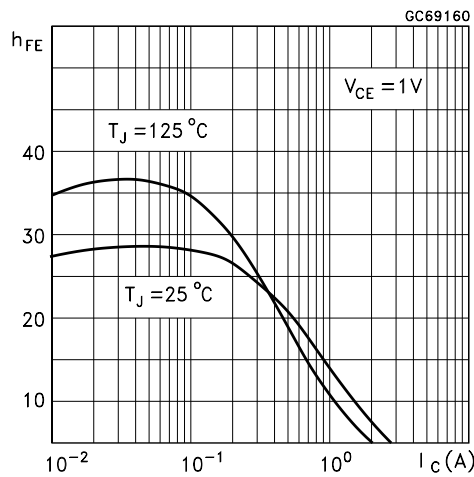
Safe Operating Areas



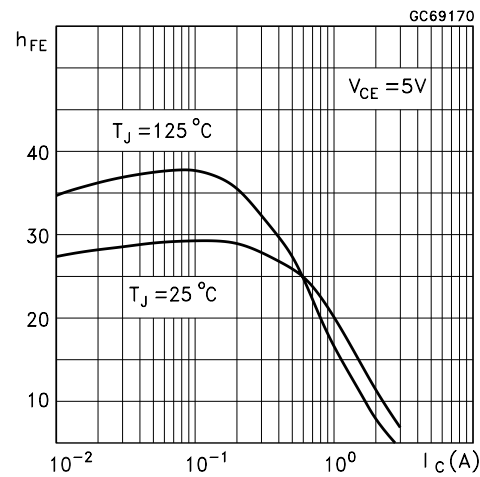
Derating Curve



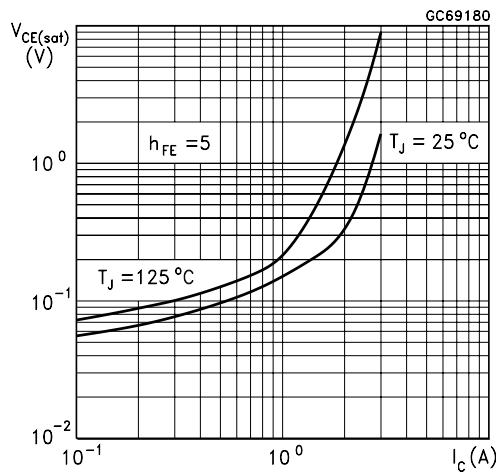
DC Current Gain



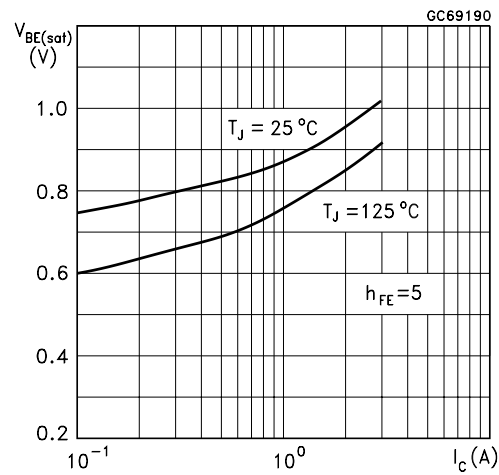
DC Current Gain



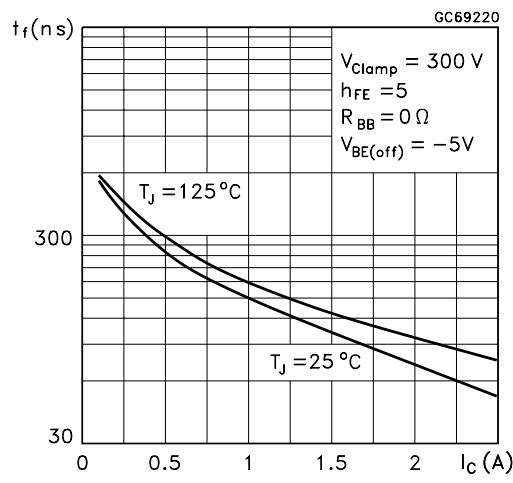
Collector Emitter Saturation Voltage



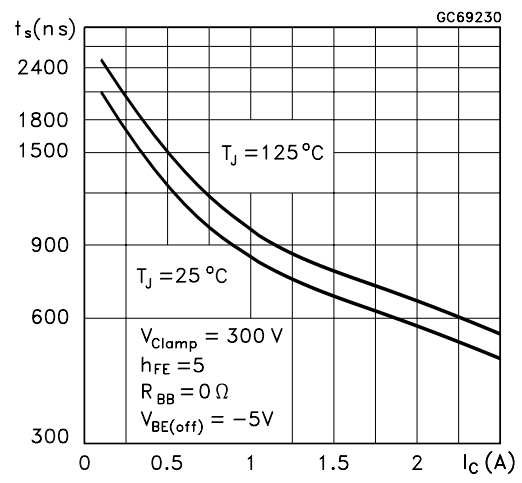
Base Emitter Saturation Voltage



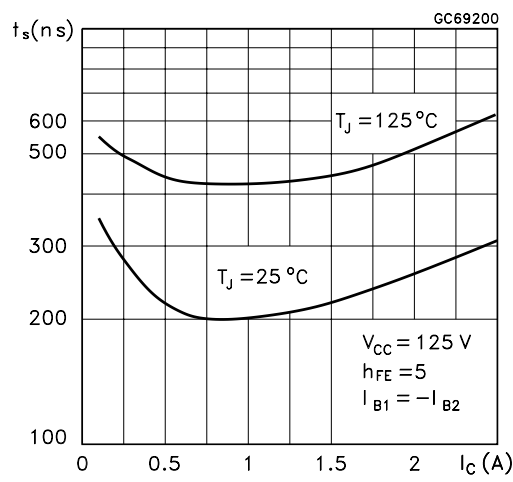
Inductive Fall Time



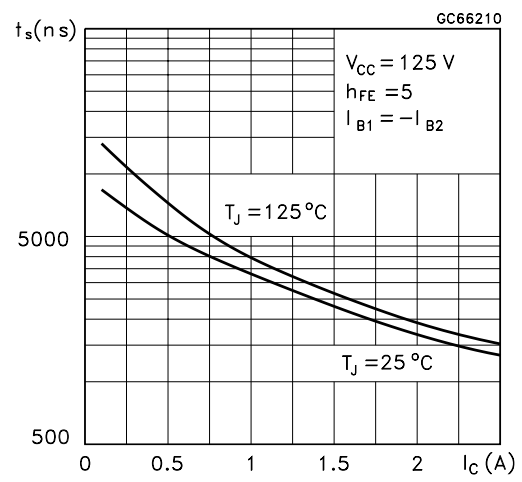
Inductive Storage Time



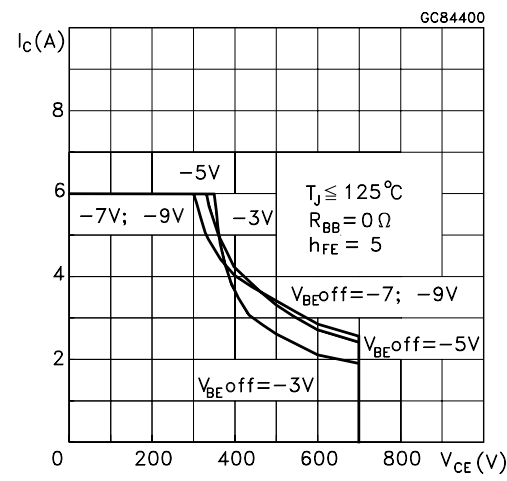
Resistive Fall Time

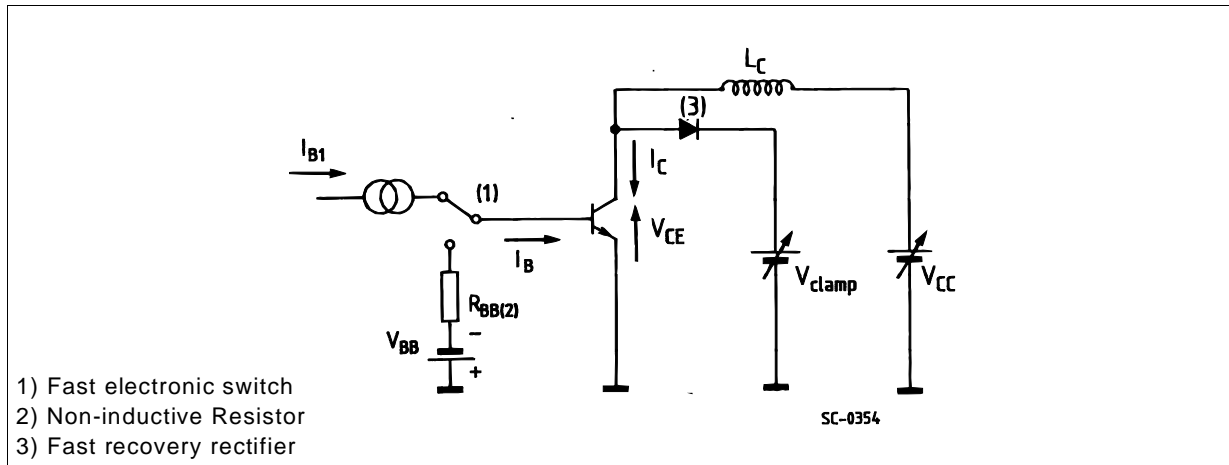
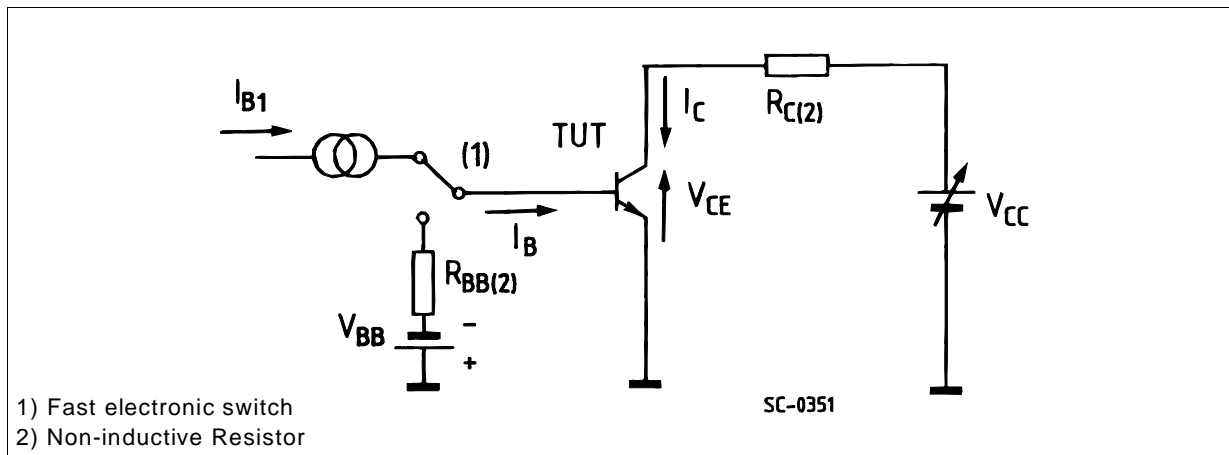


Resistive Load Storage Time



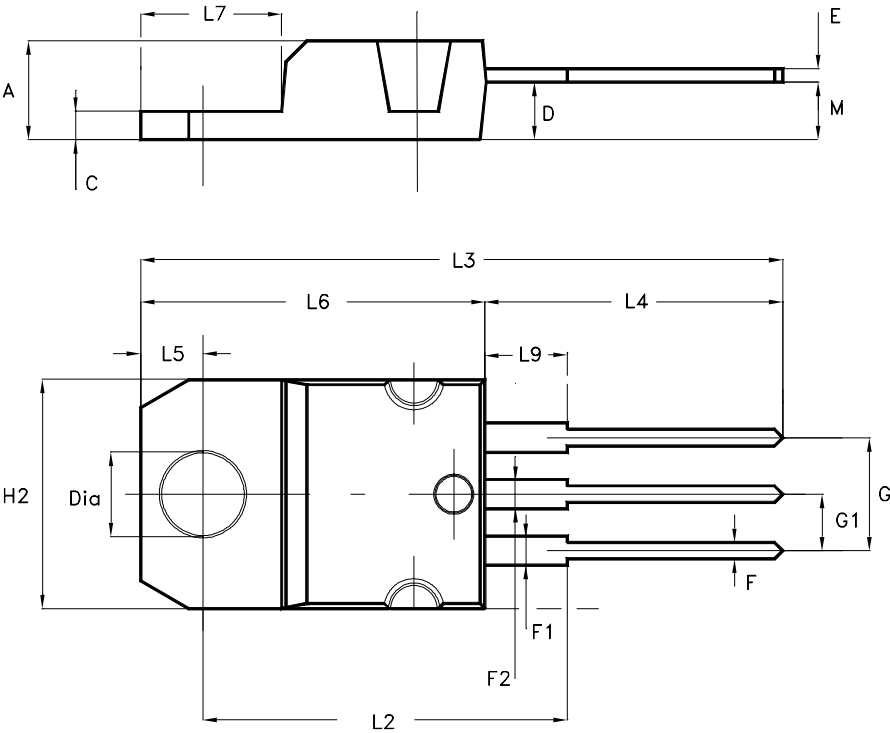
Reverse Biased SOA



**Figure 1:** Inductive Load Switching Test Circuit.**Figure 2:** Resistive Load Switching Test Circuit.

TO-220 MECHANICAL DATA

DIM.	mm			inch		
	MIN.	TYP.	MAX.	MIN.	TYP.	MAX.
A	4.40		4.60	0.173		0.181
C	1.23		1.32	0.048		0.052
D	2.40		2.72	0.094		0.107
E	0.49		0.70	0.019		0.027
F	0.61		0.88	0.024		0.034
F1	1.14		1.70	0.044		0.067
F2	1.14		1.70	0.044		0.067
G	4.95		5.15	0.194		0.202
G1	2.40		2.70	0.094		0.106
H2	10.00		10.40	0.394		0.409
L2		16.40			0.645	
L4	13.00		14.00	0.511		0.551
L5	2.65		2.95	0.104		0.116
L6	15.25		15.75	0.600		0.620
L7	6.20		6.60	0.244		0.260
L9	3.50		3.93	0.137		0.154
M		2.60			0.102	
DIA.	3.75		3.85	0.147		0.151



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